IN THE CLAIMS

Please cancel claims 3, 4, 13, and 23-31 and amend the remaining claims as

follows.

This listing of claims will replace all prior versions, and listings, of claims in

the application:

Listing of Claims:

1. (Currently amended) A test contactor comprising:

a base layer having at least one conductive post extending

therethough;

at least one block on the base layer comprising a conductive material

and a first non-conductive material covering the conductive material, the at least one

block defining at least one wall of a well to receive a device to be tested; tested, a

surface of the base layer defining a floor of the well, the conductive material being

connected to the at least one conductive post; and

non-conductive material covering the conductive material; and

at least one a plurality of electrical contact extending from the

conductive material, to be electrically coupled to a ground plane. connectors

supported by the base layer and adjacent to the well to electrically couple the device

to be tested to test circuitry.

2. (Currently amended) The test contactor of claim 1, further comprising a

wherein the base layer comprises a second of non-conductive material supporting

the non-conductive material.

Inventor(s): Fern Nee Tan, et al.

Examiner: Nguyen, Vinh P. Application No.: 10/015,980 -3/13-Art Unit: 2829 3 - 4. (Cancelled)

5. (Original) The test contactor of claim 4, wherein the electrical

connectors are pins extending into the well.

6. (Original) The test contactor of claim 1, wherein the device to be tested

has a first height and the wall of the well has a second height greater than the first

height.

7. (Original) The test contactor of claim 6, wherein the second height is at

least twice the height of the first height.

8. (Original) The test contactor of claim 7, wherein the conductive

material is aluminum.

9. (Original) The test contactor of claim 8, wherein the non-conductive

material is an anodized coating of the aluminum.

10. (Original) The test contactor of claim 9, wherein the anodized coating

has a thickness of about 35 microns to about 50 microns.

11. (Original) The test contactor of claim 1, wherein the conductive

material is aluminum.

12. (Original) The test contactor of claim 11, wherein the non-conductive

material is an anodized coating of aluminum.

Inventor(s): Fern Nee Tan, et al. Application No.: 10/015,980

Art Unit: 2829

13. (Cancelled)

- 14. (Currently amended) The test contactor of claim 1, wherein the conductive material at least one block defines a plurality of walls of the well and a gap between adjacent walls.
 - 15. (Currently amended) A test contactor comprising:

a base layer having a plurality of conductive material posts extending therethrough;

a plurality of blocks on the base layer, each block comprising a conductive material having a first height and non-conductive material, wherein the conductive material is embedded in the non-conductive material and the embedded covering the conductive material, each block defining defines at least one wall of a well to receive a device to be tested; tested having a second height, the conductive material of each block being connected to at least one of the conductive posts, a surface of the base layer defining a floor of the well, the first height being greater than the second height; and

a second conductive material supporting the embedded conductive material, wherein the second conductive material defines a floor of the well; at least one electrical contact extending from the embedded conductive material, through the second conductive material, to be coupled to ground; and electrical connectors supported by the second conductive material, adjacent to the well, to electrically couple the device to be tested to test circuitry; wherein the device to be tested has a first height and the conductive material of the wall has a second height greater than the first height.

a plurality of electrical connectors supported by the base layer and adjacent to the well to electrically couple the device to be tested to test circuitry.

16. (Currently amended) The test contactor of claim 15, comprising a

plurality of blocks of embedded conductive material, wherein each block being is

separated from an adjacent block and each block defining defines a separate wall of

the well, the blocks defining spaces between the walls and each block having a

respective electrical contact extending therefrom to be coupled to ground.

17. (Original) The test contactor of claim 16, wherein the plurality of blocks

are connected by embedded conductive material.

18. (Original) The test contactor of claim 17, wherein the second height is at

least twice as large as the first height.

19. (Original) The test contactor of claim 18, wherein the conductive material

is aluminum.

20. (Original) The test contactor of claim 19, wherein the first non-conductive

material is an anodized coating of aluminum.

21. (Original) The test contactor of claim 18, wherein the second non-

conductive material is a plastic.

22. (Original) The test contactor of claim 15, wherein the electrical contacts

are pins extending into the well.

23-31. (Cancel)